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Specification for Approval

Customer:	
Model Name:	

Sı	upplier Approv	Customer approval	
R&D Designed	R&D Approved		
Peter	Peng Jun		



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Revision Record

REV NO.	REV DATE	CONTENTS	Note
Α	2023-12-25	NEW ISSUE	

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1. Scope

This specification defines general provisions as well as inspection standards for TFT module supplied by AMSON electronics.

If the event of unforeseen problem or unspecified items may occur, naturally shall negotiate and agree to solution

2. General Information

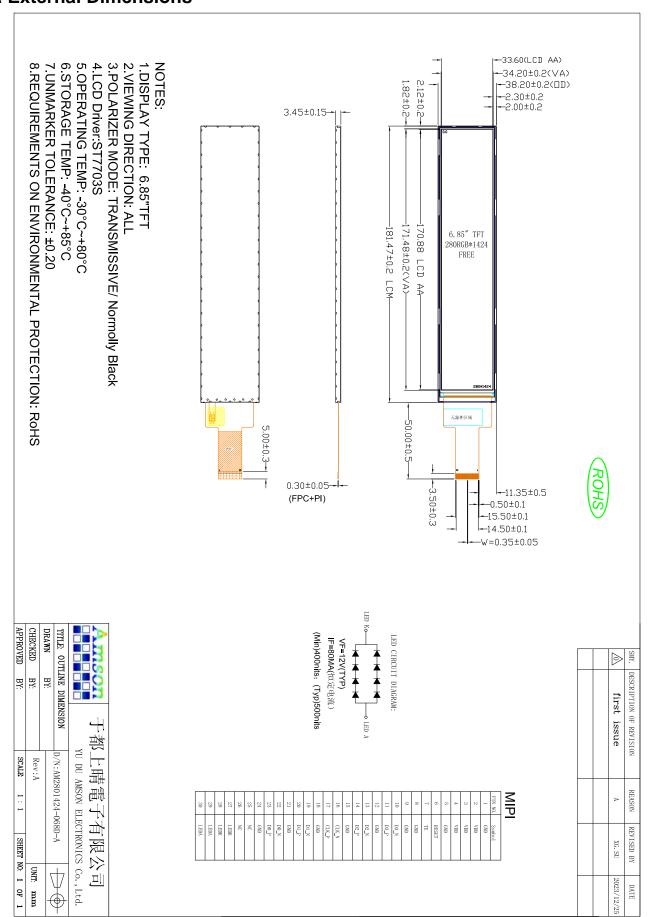
ITEM	STANDARD VALUES	UNITS
LCD type	6.85"TFT	
Dot arrangement	280×3(RGB)×1424	dots
color filter array	RGB vertical stripe	
Display mode	IPS/Normally Black	
Viewing Direction	85/85/85	
Module size	38.2(W) × 181.47(H) × 3.45(T)	mm
Active area	33.6 (H)* 170.88 (V)	mm
Dot pitch	0.09525(H) × 0.09525(V)	
Operation Voltage	3.3 V/1.8V	
Interface	4 Lanes MIPI Interface	
Backlight	White LED x 8	
Operating temperature	-30 ~ +80	°C
Storage temperature	-40 ~ +85	°C



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3. External Dimensions





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4. Interface Description

	ace Descrip	Alon .
PIN	PIN NAME	DESCRIPTION
1	GND	Power ground
2	VDD	A supply voltage to the analog circuit.3.3V
3	VDD	A supply voltage to the analog circuit.3.3V
4	IOVCC	A supply voltage to the analog circuit.1.8V or 3.3V
5	GND	Power ground
6	/RESET	Reset pin.
7	TE	NC
8	GND	Power ground
9	GND	Power ground
10	MIPI_D3N	MIPI differential data input(Negative)
11	MIPI_D3P	MIPI differential data input(Positive)
12	GND	Power ground
13	MIPI_D2N	MIPI differential data input(Negative)
14	MIPI_D2P	MIPI differential data input(Positive)
15	GND	Power ground
16	MIPI_CLKN	MIPI differential clock input(Negative)
17	MIPI_CLKP	MIPI differential clock input(Positive)
18	GND	Power ground
19	MIPI_D1N	MIPI differential data input(Negative)
20	MIPI_D1P	MIPI differential data input(Positive)
21	GND	Power ground
22	MIPI_D0N	MIPI differential data input(Negative)
23	MIPI_D0P	MIPI differential data input(Positive)
24	GND	Power ground
25	NC	NC
26	NC	NC
27	LEDK	LED backlight (Cathode).
28	LEDK	LED backlight (Cathode).
29	LEDA	LED backlight (Anode).
30	LEDA	LED backlight (Anode).



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5. Absolute Maximum Ratings

Item	Symbol	Min.	Max.	Unit
TFT Analog Supply Voltage	VDD	-0.3	3.6	V
Input Voltage	Vin	-0.3	VCI +0.3	V
Operating Temperature	Тор	-30	80	°C
Storage Temperature	Тѕт	-30	80	°C
Storage Humidity	HD	20	90	%RH

6. DC Characteristics

Item	Symbol	Min.	Тур.	Max.	Unit	Remark
TFT Analog Supply Voltage	VDD	2.5	3.3	3.6	V	-
TFT I/O Supply Voltage	VDDIO	1.7	1.8	1.9	V	
CTP Analog Supply Voltage	VDD	2.7	3.3	3.6	V	
Input High Voltage	V _{IH}	0.7 VDD	-	VDD	V	-
Input Low Voltage	V _{IL}	0	-	0.3 VDD	V	-
Output High Voltage	V _{OH}	0.7 VDD	-	VDD	V	-
Output Low Voltage	V _{OL}	0	-	0.3 VDD	V	-
I/O Leak Current	ILI	-0.1	-	0.1	uA	-

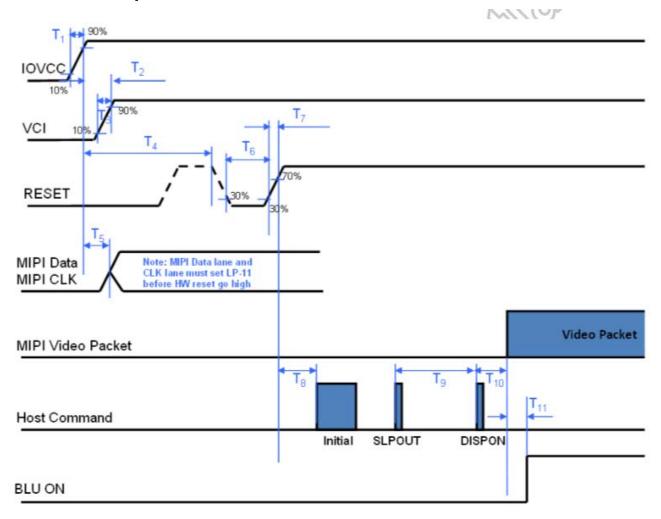
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7. Timing Characteristics

7.1. Power ON/OFF Sequence

Power ON Sequence

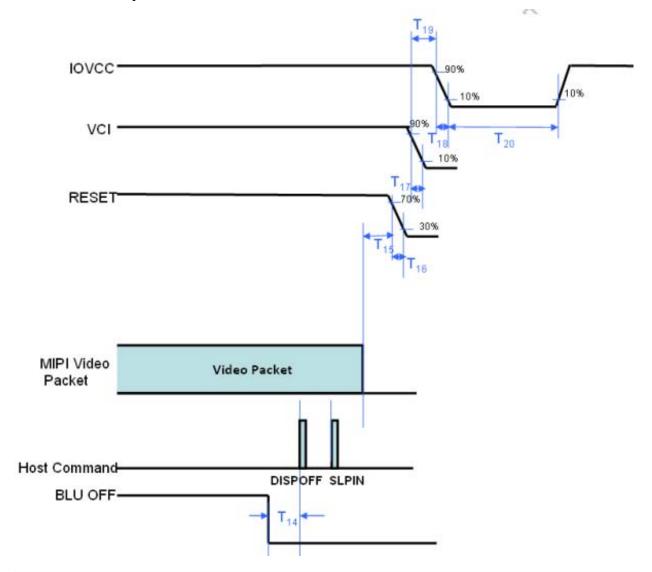


	Min.	Тур.	Max.	Unit
T1	0.01	-	10	ms
T2		No Limit		ms
Т3	0.01	-	10	ms
T4	1	-	-	ms
T5	1	-	-	ms
Т6	10	-	-	us
T7		No Limit		ns
Т8	15	-	-	ms
Т9	120	-	-	ms
T10	No Limit			ms
T11	100	150	-	ms

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Power OFF Sequence



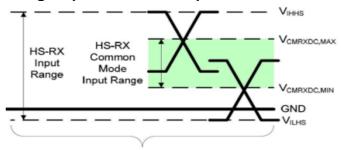
	Min.	Тур.	Max.	Unit		
T14	40	100	-	ms		
T15	10	-	-	ms		
T16		No Limit	ms			
T17	No Limit ms					
T18	No Limit ms					
T19		ms				
T20	500			ms		

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7.2 MIPI Characteristics

7.2.1 DC Specifications High-Speed Receiver Specification



High Speed Receiver

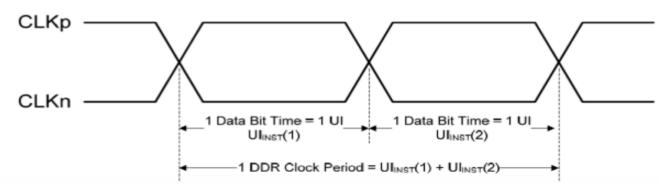
Parameter	Description	Min	Nom	Max	Units	Note
VCMRX(DC)	Common-mode voltage for HS receiver			330	mV	1,2
VIDTH	Differential input high threshold			70	mV	
VIDTL	DTL Differential input low threshold				mV	
VIHHS Single-ended input high voltage				460	mV	1
VILHS	VILHS Single-ended input low voltage				mV	1
ZID	Differential input impedance	80	100	125	Ω	

Notes:

- 1. Excluding possible additional RF interference of 100mV peak sine wave beyond 450MHz.
- 2. Values in this table include a ground difference of 50mV between the transmitter and the receiver, the static common-mode level tolerance and variations below 450MHz

7.2.2 Forward high speed transmissions

DDR Clock Definition



Clock Parameter	Symbol	Min	Тур	Max	Units	Notes
UI instantaneous	UI _{INST}			12.5	ns	1,2

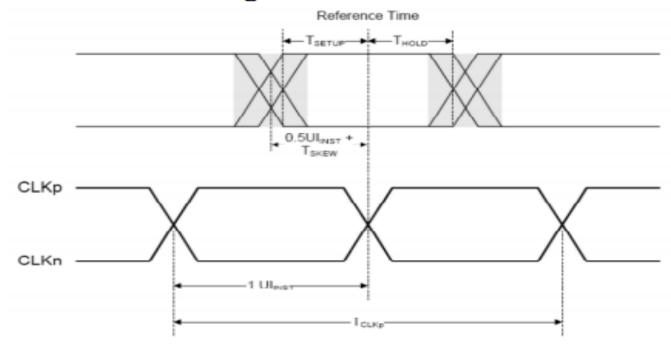
Notes:

- 1. This value corresponds to a minimum 80 Mbps data rate.
- 2. The minimum UI shall not be violated for any single bit period, i.e., any DDR half cycle within a data burst.

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Data to Clock Timing Definitions

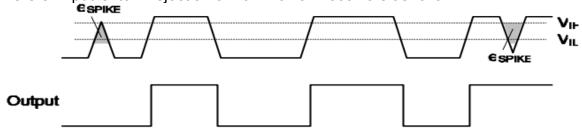


7.2.3 Low power transceiver specifications

Parameters	ameters Symbol Condition		Min	Тур	Max	Unit
Logic high level input voltage	VIHCD	Contention Detection (Lane_D0)	450		1350	mV
Logic low level input voltage	VILCD	Contention Detection (Lane_D0)	0		200	mV
Logic high level input voltage	VIH-LPRX	LP-Rx (Lane_CK, Lane_D0, Lane_D1)	880	-	1350	mV
Logic low level input voltage	VIL-LPRX	LP-Rx (Lane_CK, Lane_D0, Lane_D1			550	mV
Logic low level input voltage	VIL-ULPS	LP-Rx ULPS (Lane_CK, Lane_D0, Lane_D1)	0		300	mV
Logic high level input voltage	VOH-LPTX	Contention Detection (Lane_D0)		1.2	1.3	V
Logic low level input voltage	VOL-LPTX	Contention Detection (Lane_D0)		0	50	mV
eSPIKE ^(1,2,3)	Fig. 2	Input pulse rejection			300	V.ps

Notes:

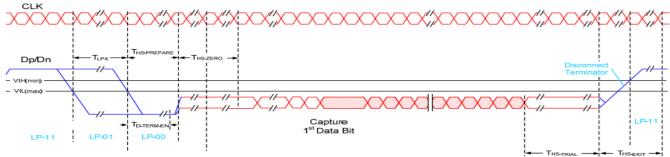
- (1) Time-voltage integration of a spike above VIL when being in LP-0 state or below VIH when being in LP-1 state an impulse less than this will not change the receiver state.
- (2) In addition to the required glitch rejection, implementers shall ensure rejection of known RF-interferers. Input Glitch Rejection of Low Power Receivers as follow.

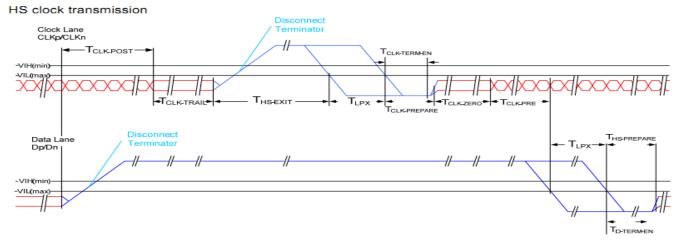


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7.3 DSI Timing Characteristics HS Data Transmission Burst





Timing Parameters:

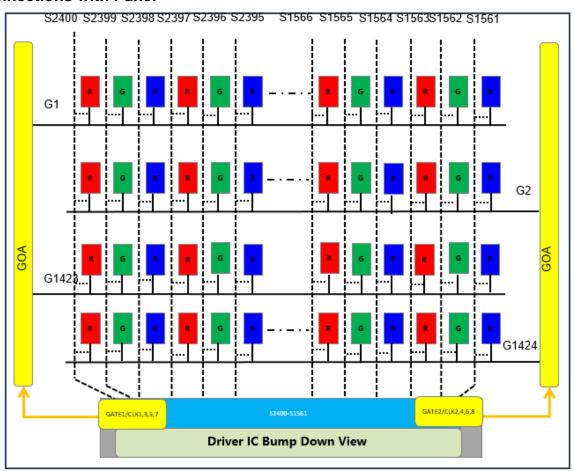
Parameter	Description	Min	Typ	Max	Unit
T _{CLK-POST}	Time that the transmitter continues to send HS clock after the last associated Data Lane has transitioned to LP Mode. Interval is defined as the period from the end of The-Trail to the beginning of Tclk-Trail.	60ns + 52*UI	.,,,,		ns
T _{CLK-TRAIL}	Time that the transmitter drives the HS-0 state after the last payload clock bit of a HS transmission burst.	60			ns
T _{HS-EXIT}	Time that the transmitter drives LP-11 following a HS burst.	300			ns
T _{CLK-TERM-EN}	Time for the Clock Lane receiver to enable the HS line termination, starting from the time point when Dn crosses V _{IL.MAX} .	Time for Dn to reach V _{TERM-EN}		38	ns
T _{CLK-PREPARE}	Time that the transmitter drives the Clock Lane LP-00 Line state immediately before the HS-0 Line state starting the HS transmission.	38		95	ns
T _{CLK-PRE}	Time that the HS clock shall be driven by the transmitter prior to any associated Data Lane beginning the transition from LP to HS mode.	8			UI
T _{CLK-PREPARE} + T _{CLK-ZERO}	T _{CLK-PREPARE} + time that the transmitter drives the HS-0 state prior to starting the Clock.	300			ns
T _{D-TERM-EN}	Time for the Data Lane receiver to enable the HS line termination, starting from the time point when Dn crosses V _{IL,MAX} .	Time for Dn to reach V _{TERM-EN}		35 ns +4*UI	
T _{HS-PREPARE}	Time that the transmitter drives the Data Lane LP-00 Line state immediately before the HS-0 Line state starting the HS transmission	40ns + 4*UI		85 ns + 6*UI	ns
T _{HS-PREPARE} + T _{HS-ZERO}	T _{HS-PREPARE} + time that the transmitter drives the HS-0 state prior to transmitting the Sync sequence.	145ns + 10*UI			ns
T _{HS-TRAIL}	Time that the transmitter drives the flipped differential state after last payload data bit of a HS transmission burst	60ns + 4*UI			ns

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7.4 PARALLEL INPUT TIMING TABLE

Connections with Panel





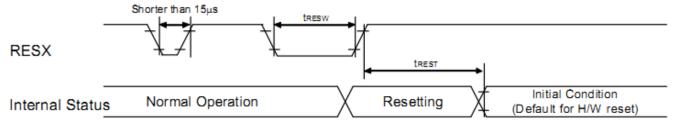
TIMING

1 11411140								
Symbol	Min.	Тур	Max.	Unit				
Fdclk	45	50	67	MHz				
Тно		1424		DCLK				
THPW	15	30	40	DCLK				
Тнвр	40	60	88	DCLK				
Тнгр	12	40	132	DCLK				
Tvd	600			Н				
Tvpw	2	3	20	Н				
Тувр	8	15	23	Н				
TVFP	1	15	49	Н				
	FDCLK THD THPW THBP THFP TVD TVPW TVBP	FDCLK 45 THD THPW 15 THBP 40 THFP 12 TVD TVPW 2 TVBP 8	FDCLК 45 50 THD 1424 THPW 15 30 THBP 40 60 THFP 12 40 TVD 600 TVPW 2 3 TVBP 8 15	FDCLК 45 50 67 THD 1424 THPW 15 30 40 THBP 40 60 88 THFP 12 40 132 TVD 600 TVPW 2 3 20 TVBP 8 15 23				

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7.5 Reset Timing Characteristics



Reset timing:

IOVCC=1.65V to 3.6V, AGND=DGND=0V, Ta=-40 to 85°C

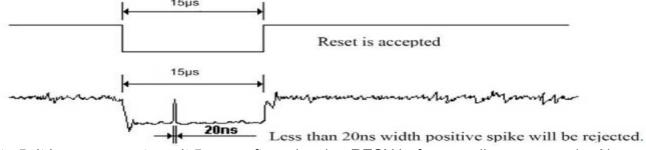
Symbol	Parameter	Related Pins	MIN	TYP	MAX	Note	Unit
t _{RESW}	*1) Reset low pulse width	RESX	15	-	-		μS
t _{REST} *2) Reset complete time	10.5	-	-	-	5	When reset applied during sleep-in mode	ms
	2) Reset complete time	-		-	120	When reset applied during sleep-out mode	ms

RESX Pulse	Action
Shorter than 5µs	Reset Rejected
Longer than 15µs	IC Reset
Detween Fire and 15	Reset starts
Between 5μs and 15μs	(It depends on voltage and temperature condition.)

Note 1) Spike due to an electrostatic discharge on RESX line does not cause irregular system reset according to the table below.

Note 2) During the resetting period, the display will be blanked (The display is entering blanking sequence, which maximum time is 120 ms, when Reset Starts in Sleep Out –mode. The display remains the blank state in Sleep In –mode) and then return to Default condition for H/W reset. Note 3) During Reset Complete Time, data in MTP will be latched to internal register during this period. This loading is done every time when there is H/W reset complete time (tREST) within 5ms after a rising edge of RESX.

Note 4) Spike Rejection also applies during a valid reset pulse as shown below:



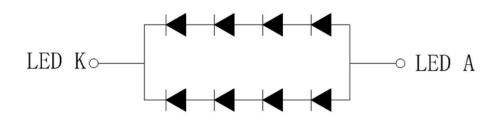
Note 5. It is necessary to wait 5msec after releasing RESX before sending commands. Also Sleep Out command cannot be sent for 120msec.

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8. Backlight Characteristic

LED CIRCUIT DIAGRAM:



Item	Symbol	MIN	TYP	MAX	UNIT	Test Condition
Supply Voltage	Vf	10.8	12	13.2	V	If=80mA
Supply Current	If	-	80	-	mA	-
Luminous Intensity for LCM	-	400	500	-	cd/m ²	If=80mA
Uniformity for LCM	-	-	80	-	%	If=80mA
Life Time	-	-	50000	-	Hr	If=80mA
Backlight Color	White					



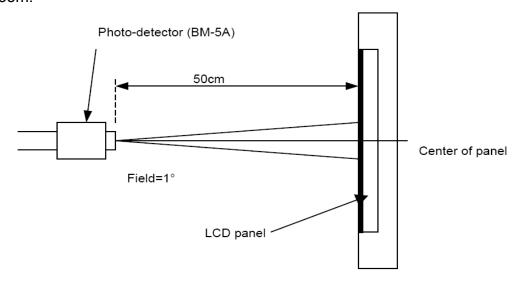
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9. Optical Characteristics

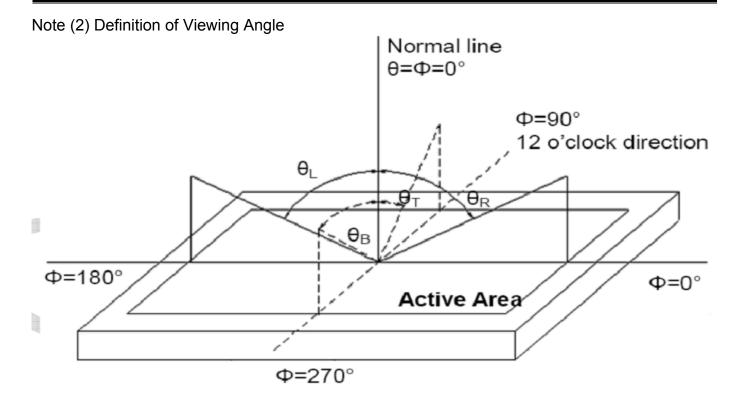
Item	Conditions		Min.	Тур.	Max.	Unit	Note	
	Horizontal	θL	ı	85	-			
Viewing Angle	Honzontai	θR	-	85	-	dograa	(4) (2) (6)	
(CR>10)	Vertical	θт	-	85	-	degree	(1),(2),(6)	
	vertical	θв	-	85	-			
Contrast Ratio	Center		1000	1200	-	-	(1),(3),(6)	
Doggongo Timo	Rising			30	35	mo	(1) (4) (6)	
Response Time	Falling		-		35	ms	(1),(4),(6)	
	Red x			-	-	-		
	Red y			-		-		
	Green x			-		-		
CF Color	Green y			-		-	(4) (6)	
Chromaticity (CIE1931)	Blue x		Тур.	-	Тур.	-	(1), (6)	
(3.2.33.)	Blue y		-0.05	-	+0.05	-		
	White x			0.319		-		
	White y			0.329	<u> </u>	-		

Note (1) Measurement Setup: The LCD module should be stabilized at given temp. 25°C for 15 minutes to avoid abrupt temperature change during measuring. In order to stabilize the luminance, the measurement should be executed after lighting backlight for 15 minutes in a windless room.



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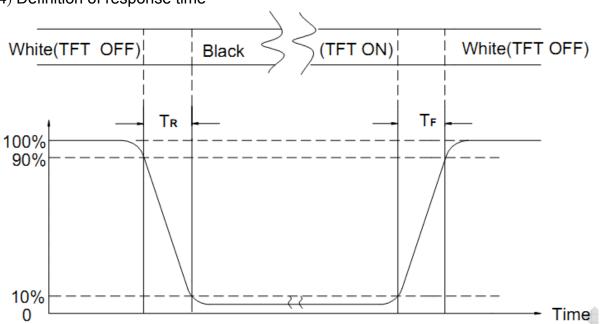


Note (3) Definition of Contrast Ratio (CR)

The contrast ratio can be calculated by the following expression Contrast Ratio (CR) = L63 / L0

L63: Luminance of gray level 63, L0: Luminance of gray level 0

Note (4) Definition of response time



Note (5) Definition of Transmittance (Module is without signal input)

Transmittance = Center Luminance of LCD / Center Luminance of Back Light x 100%

Note (6) Definition of color chromaticity (CIE1931)

Color coordinates measured at the center point of LCD



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10. Reliability Test Conditions and Methods

NO.	TEST ITEMS	TEST CONDITIONS	INSPECTION AFTER TEST
?	High Temperature Storage	80°C±2°C×96Hours	
?	Low Temperature Storage	-30°C±2°C×96Hours	
?	High Temperature Operating	80°C±2°C×96Hours	Inspection after 2~4hours
?	Low Temperature Operating	-30°C±2°C×96Hours	storage at room temperature, the samples should be free from defects:
?	Temperature Cycle (Storage)	-20°C 25°C 70°C (30min.) 1cycle Total 10cycle	 Air bubble in the LCD. Seal leak. Non-display. Missing segments. Glass crack.
?	Damp Proof Test (Storage)	50°C±5°C×90%RH×120Hours	6. Current IDD is twice higher than initial value.
?	Vibration Test	Frequency:10Hz~55Hz~10Hz Amplitude:1.5MM X, Y, Z direction for total 3hours (Packing condition test will be tested by a carton)	7. The surface shall be free from damage.8. The electric characteristic requirements shall be
?	Drooping Test	Drop to the ground from 1M height one time every side of carton. (Packing condition test will be tested by a carton)	satisfied.
?	ESD Test	Voltage: ±8KV, R:330Ω, C:150PF, Air Mode,10times	

REMARKS:

- 1. The Test samples should be applied to only one test item.
- 2. Sample side for each test item is 5~10pcs.
- 3. For Damp Proof Test, Pure water (Resistance $> 10M\Omega$) should be used.
- 4. In case of malfunction defect caused by ESD damage, if it would be recovered to normal state after resetting, it would be judged as a good part.
- 5. EL evaluation should be accepted from reliability test with humidity and temperature: Some defects such as black spot/blemish can happen by natural chemical reaction with humidity and Fluorescence EL has.
- 6. Failure Judgment Criterion: Basic Specification Electrical Characteristic, Mechanical Characteristic, Optical Characteristic.



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11. Inspection Standard

11.1. Quality

The quality of goods supplied to purchaser shall come up to the following standards:

11.1.1. Inspection Tools and Instruments

Vernier calipers, film scales, multimeter, magnifying eyepiece, ND5%, luminance meter and so on.

11.1.2. The Method of Preserving Goods

After delivery of goods from UNI Display to purchaser, purchaser shall keep the LCM at -10°C to 30°C, and it might be desirable to keep at the normal room temperature and humidity until incoming inspection or throwing into process line.

11.1.3. Incoming Inspection

(A) The methods of Inspection

If purchaser makes an incoming inspection, a sampling plan shall be applied on the condition that quality of one delivery shall be regarded as one lot.

(B) The standard of quality:

ISO-2859-1 (same as MIL-STD-105E), Level: II

CLASS	AQL (%)
Critical	0.4 %
Major	0.65 %
Minor	1.5 %

Every item shall be inspected according to the class.

(C) Measure

If as the result of above receiving inspection, a lot out is discovered, purchaser Shall inform seller of it within seven days. But first shipment within fourteen days.

11.1.4. Warranty Policy

UNI Display will provide one-year warranty for the products only if under Specification operating conditions. UNI Display will replace new products for these defect products which are under warranty period and belong to the responsibility of UNI Display.

11.2. Checking Condition

- **11.2.1** Checking direction shall be in the 45 degree area to face the sample.
- **11.2.2** Inspector shall see from over 300±25mm with bare eyes far from the sample.

11.2.3 Ambient Illumination:

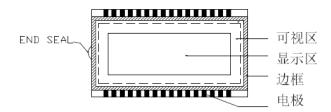
0 ~30 Lux for functional inspection 500 ~ 1200 Lux for external appearance inspection.



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11.2.4 Test Area:



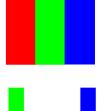
- 11.2.5 Inspection should be carried out with rope electrostatic ring and static tinger cover (both hands except small fingers must be worn.)
- 11.2.6 The inspector may make a visual inspection or a comparative examination with a film ruler and a magnifying eyepiece. Individual defects shall be determined according to the limited samples.
- **11.2.7** Functional testing uses electrical testing fixtures or test fixtures required by customers.
- **11.2.8** The ion fan should be used when testing.

11.2.9 The principle of judgement:

- 11.2.9.1 If the defect outside the visual area does not affect the assembly and display, it will be judged as a good product.
- 11.2.9.2 Poor definition:

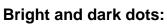
Pixel:

A combination of three sub-pixels (Red + Green + Blue).



Dot:

Any of the sub-pixels (Red or Green or Blue).



A point pixel (sub-pixel: R, G, B pixels) is lit or turned off during the display function test.

Highlights:

Usually considered to be shown on a black screen.

Dark spots:

They are generally considered to be shown on R, G, B solid colors or white images.

Neighborhood:

Two or three adjacent point pixels (dot: sub-pixel) connected together (R, G or G, B or B, R or RGB).



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11.3 Inspection Plans:

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CLASS	ITEM	JUDGEMENT	CLASS
PACKING &	OUTSIDE AND INSIDE PACKAGE	"MODEL NO." , "LOT NO." AND "QUANTITY" SHOULD INDICATE ON THE PACKAGE.	Minor
INDICATE	2. MODEL MIXED AND QUANTITY	OTHER MODEL MIXEDREJECTED QUANTITY SHORT OR OVERREJECTED	Critical
	3. PRODUCT INDICATION	"MODEL NO." SHOULD INDICATE ON THE PRODUCT	Major
ASSEMBLY	DIMENSION, LCD GLASS SCRATCH AND SCRIBE DEFECT.	ACCORDING TO SPECIFICATION OR DRAWING.	Major
	5. VIEWING AREA	POLARIZER EDGE OR LCD'S SEALING LINE IS VISABLE IN THE VIEWING AREAREJECTED	Minor
	6. BLEMISH - BLACK SPOT - WHITE SPOT IN THE LCD AND LCD GLASS CRACKS	ACCORDING TO STANDARD OF VISUAL INSPECTION(INSIDE VIEWING AREA)	Minor
APPEARANCE	7. BLEMISH - BLACK SPOT WHITE SPOT AND SCRATCH ON THE POLARIZER	ACCORDING TO STANDARD OF VISUAL INSPECTION(INSIDE VIEWING AREA)	Minor
	8. BUBBLE IN POLARIZER	ACCORDING TO STANDARD OF VISUAL INSPECTION(INSIDE VIEWING AREA)	Minor
	9. LCD'S RAINBOW COLOR	STRONG DEVIATION COLOR (OR NEWTON RING) OF LCDREJECTED. OR ACCORDING TO LIMITED SAMPLE (IF NEEDED, AND INSIDE VIEWING AREA)	Minor
	10. ELECTRICAL AND OPTICAL CHARACTERISTICS (CONTRAST, VOP, CHROMATICITY ETC)	ACCORDING TO SPECIFICATION OR DRAWING . (INSIDE VIEWING AREA)	Critical
ELECTRICAL	11.MISSING LINE	MISSING DOT: LINE : CHARACTERREJECTED	Critical
	12.SHORT CIRCUIT WRONG PATTERN DISPLAY	NO DISPLAY - WRONG PATTERN DISPLAY - CURRENT CONSUMPTION OUT OF SPECIFICATION REJECTED	Critical
	13. DOT DEFECT (FOR COLOR AND TFT)	ACCORDING TO STANDARD OF VISUAL INSPECTION	Minor



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11.4 Inspection Plans:

NO.	pection F	ITEM	JUDGEMENT				
1101	02/100				 		
			(A) ROUN	ID TYPE:	unit: mm		
			DIAN	METER (mm.)	ACCEPTABLE Q'TY		
				Ø≤0.2	Distances ≥ 1mm		
				$2 < \varnothing \le 0.3$	3 (Distance ≥ 5mm)		
		BLACK AND WHITE	0.	$3 < \varnothing \le 0.4$	2 (Distance ≥ 5mm)		
		SPOT FOREIGN	0.	4 < Ø	0		
11.4.1	MINOR	MATERIEL DUST IN	NOT	E: ∅=(LENGTH*W	IDTH)/2		
		THE CELL BLEMISH SCRATCH	(S) LINE	TYPE:	unit: mm		
			LENGTH	WIDTH	ACCEPTABLE QTY		
				W ≤ 0.03	3 Distance≥ 1mm		
			L ≤4.0	$0.03 < W \le 0.05$	3 (Distanced ≥ 15mm)		
				0.05 < W	FOLLOW ROUND TYPE		
			NOTE: Ø	=(LENGTH*WIDTH	1)/2		
					unit: mm.		
			DIAMETER		ACCEPTABLE Q'TY		
		BUBBLE IN POLARIZER DENT ON POLARIZER	Ø<0.2		Distance≥ 1mm		
11.4.2	MINOR		0.2<∅≤ 0.3		4 (Distance≥ 15mm)		
			0.3<∅≤ 0.4		3 (Distance≥ 15mm)		
			0.4<Ø		0		
				Items	ACC. Q'TY		
				Bright dot	N ≤1 (Distance ≥ 15mm)		
			Dark dot		N ≤3 (Distance ≥ 15mm)		
11.4.3	MINOR	Dot Defect	Pixel Define: Note 1: The definition of dot: The size of a defective dot ov dot is regarded as one defective dot. Definition:<1. visible by 5% ND filter 2: Bright dot: Dots appear bright and unchanged in LCD panel is displaying under black pattern. 3: Dark dot: Dots appear dark and unchanged in standard LCD panel is displaying under pure red. green 、blue				
11.4.4	MINOR	Mura		e through 5% ND necessary	filter in 50% gray or judge by limit		



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NO.	CLASS	ITEM	JUDGEN	MENT	
11.4.5	MINOR	LCD GLASS CHIPPING	S S	X≥3mm Y>S	Reject
11.4.6	MINOR	LCD GLASS CHIPPING	S. T.	X OR Y >S	Reject
11.4.7	MINOR	LCD GLASS CRACK	Y	Continuous burst NG	Reject
11.4.8	MINOR	LCD GLASS SCRIBE DEFECT	Λ	According to dimension	Reject
11.4.9	MINOR	LCD GLASS CHIPPING (on the terminal area)	T	Y<1/2Z Y≥0.5mm X≥3mm	Reject
11.4.10	MINOR	LCD GLASS CHIPPING (on the terminal surface)	T Z X	Y<1/2Z Y≥0.5mm X≥3mm	Reject
11.4.11	MINOR	LCD GLASS CHIPPING		X≥3mm Y>T the electrode retain the e lines	



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12. Handling Precautions

12.1 Mounting method

The LCD panel of AMSON TFT module consists of two thin glass plates with polarizes which easily be damaged. And since the module in so constructed as to be fixed by utilizing fitting holes in the printed circuit board.

Extreme care should be needed when handling the LCD modules.

12.2 Caution of LCD handling and cleaning

When cleaning the display surface, Use soft cloth with solvent

[Recommended below] and wipe lightly

- Isopropyl alcohol
- Ethyl alcohol

Do not wipe the display surface with dry or hard materials that will damage the polarizer surface.

Do not use the following solvent:

- Water
- Aromatics

Do not wipe ITO pad area with the dry or hard materials that will damage the ITO patterns Do not use the following solvent on the pad or prevent it from being contaminated:

- Soldering flux
- Chlorine (CI) , Sulfur (S)

If goods were sent without being silicon coated on the pad, ITO patterns could be damaged due to the corrosion as time goes on.

If ITO corrosion happen by miss-handling or using some materials such as Chlorine (CI), Sulfur (S) from customer, Responsibility is on customer.

12.3 Caution against static charge

The LCD module use C-MOS LSI drivers, so we recommended that you:

Connect any unused input terminal to power or ground, do not input any signals before power is turned on, and ground your body, work/assembly areas, and assembly equipment to protect against static electricity.

12.4 packing

- Module employs LCD elements and must be treated as such.
- Avoid intense shock and falls from a height.
- To prevent modules from degradation, do not operate or store them exposed direct to sunshine or high temperature/humidity

12.5 Caution for operation

- It is an indispensable condition to drive LCD's within the specified voltage limit since the higher voltage then the limit cause the shorter LCD life.
- An electrochemical reaction due to direct current causes LCD's undesirable deterioration, so that the use of direct current drive should be avoided.
- Response time will be extremely delayed at lower temperature then the operating temperature range and on the other hand at higher temperature LCD's how dark color in them. However those phenomena do not mean malfunction or out of order with LCD's, which will come back in the specified operation temperature.
- If the display area is pushed hard during operation, some font will be abnormally displayed but it resumes normal condition after turning off once.
- Slight dew depositing on terminals is a cause for electro-chemical reaction resulting in terminal open circuit.
 - Usage under the maximum operating temperature, 50%Rh or less is required.



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12.6 storing

In the case of storing for a long period of time for instance, for years for the purpose or replacement use, the following ways are recommended.

- Storage in a polyethylene bag with the opening sealed so as not to enter fresh air outside in it. And with no desiccant.
- Placing in a dark place where neither exposure to direct sunlight nor light's keeping the storage temperature range.
- Storing with no touch on polarizer surface by the anything else.
 [It is recommended to store them as they have been contained in the inner container at the time of delivery from us

12.7 Safety

- It is recommendable to crash damaged or unnecessary LCD's into pieces and wash off liquid crystal by either of solvents such as acetone and ethanol, which should be burned up later.
- When any liquid leaked out of a damaged glass cell comes in contact with your hands, please wash it off well with soap and water

13. Precaution for Use

13.1

A limit sample should be provided by the both parties on an occasion when the both parties agreed its necessity. Judgment by a limit sample shall take effect after the limit sample has been established and confirmed by the both parties.

13.2

On the following occasions, the handing of problem should be decided through discussion and agreement between responsible of the both parties.

- When a question is arisen in this specification.
- When a new problem is arisen which is not specified in this specifications?
- When an inspection specifications change or operating condition change in customer is reported to AMSON TFT and some problem is arisen in this specification due to the change.
- When a new problem is arisen at the customer's operating set for sample evaluation in the customer site.

14. Packing Method

TBD.